

## STD5N20L N-CHANNEL 200V - 0.65Ω - 5A DPAK STripFET™ MOSFET

### **Table 1: General Features**

TYPE	V <sub>DSS</sub>	R <sub>DS(on)</sub>	ID	Pw
STD5N20L	200 V	< 0.7 Ω	5 A	33 W

- TYPICAL R<sub>DS</sub>(on) = 0.65 Ω @ 5V
- CONDUCTION LOSSES REDUCED
- LOW INPUT CAPACIATNCE
- LOW THRESHOLD DEVICE

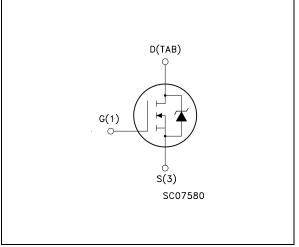
### DESCRIPTION

The STD5N20L utilizes the latest advanced design rules of ST's proprietary STripFET<sup>™</sup> technology. This is suitable for the most demanding DC Motor Control and lighting application.

### APPLICATIONS

- UPS AND MOTOR CONTROL
- LIGHTING

# Figure 1: Package



### **Table 2: Order Codes**

SALES TYPE	MARKING	PACKAGE	PACKAGING	
STD5N20LT4	D5N20L	DPAK	TAPE & REEL	

Symbol	Parameter	Value	Unit
V <sub>DS</sub>	Drain-source Voltage (V <sub>GS</sub> = 0)	200	V
V <sub>DGR</sub>	Drain-gate Voltage ( $R_{GS} = 20 \text{ k}\Omega$ )	200	V
V <sub>GS</sub>	Gate- source Voltage	±20	V
I <sub>D</sub>	Drain Current (continuous) at T <sub>C</sub> = 25°C	5	А
I <sub>D</sub>	Drain Current (continuous) at T <sub>C</sub> = 100°C	3.6	А
I <sub>DM</sub> (•)	Drain Current (pulsed)	20	А
P <sub>TOT</sub>	Total Dissipation at $T_C = 25^{\circ}C$	33	W
	Derating Factor	0.27	W/°C
T <sub>stg</sub>	Storage Temperature -55 to 150		°C
Tj	Operating Junction Temperature	-33 10 150	

### **Table 3: Absolute Maximum ratings**

(•) Pulse width limited by safe operating area

### Table 4: Thermal Data

Rthj-case	Thermal Resistance Junction-case Max	3.75	°C/W
Rthj-amb	Thermal Resistance Junction-ambient Max	100	°C/W
T <sub>I</sub> Maximum Lead Temperature For Soldering Purpose		275	°C

### **ELECTRICAL CHARACTERISTICS** ( $T_{CASE} = 25^{\circ}C$ UNLESS OTHERWISE SPECIFIED) Table 5: On/Off

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source Breakdown Voltage	$I_D = 250 \ \mu A, \ V_{GS} = 0$	200			V
I <sub>DSS</sub>		V <sub>DS</sub> = Max Rating			1	μA
	Drain Current (V <sub>GS</sub> = 0)	V <sub>DS</sub> = Max Rating, T <sub>C</sub> = 125°C			10	μA
I <sub>GSS</sub>	Gate-body Leakage Current (V <sub>DS</sub> = 0)	$V_{GS} = \pm 20V$			±100	nA
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 50 \mu A$	1		2.5	V
R <sub>DS(on)</sub>	Static Drain-source On Resistance	$V_{GS} = 5 \text{ V}, \text{ I}_{D} = 2.5 \text{ A}$		0.65	0.7	Ω

### Table 6: Dynamic

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g <sub>fs</sub> (2)	Forward Transconductance	$V_{DS} = 15 \text{ V}, \text{ I}_{D} = 5 \text{ A}$		6.5		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input Capacitance Output Capacitance Reverse Transfer Capacitance	V <sub>DS</sub> = 25V, f = 1 MHz, V <sub>GS</sub> = 0		242 44 6		pF pF pF
t <sub>d(on)</sub> t <sub>r</sub> t <sub>d(off)</sub> t <sub>f</sub>	Turn-on Delay Time Rise Time Turn-off Delay Time Fall Time	$\label{eq:VD} \begin{array}{l} V_{DD} = 100 \text{ V}, \text{ I}_{D} = 2.5 \text{ A} \\ \text{R}_{\text{G}} = 4.7\Omega, \text{ V}_{\text{GS}} = 5\text{ V} \\ (\text{Resistive Load see Figure 14}) \end{array}$		11.5 21.5 14 15.5		ns ns ns ns
Qg Qgs Qgd	Total Gate Charge Gate-Source Charge Gate-Drain Charge	$V_{DD}$ = 160 V, I <sub>D</sub> = 5 A, V <sub>GS</sub> = 5V		5 1.5 3	6	nC nC nC

### Table 7: Source Drain Diode

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub>	Source-drain Current				5	А
I <sub>SDM</sub> (*)	Source-drain Current (pulsed)				20	А
V <sub>SD</sub> (1)	Forward On Voltage	$I_{SD} = 5 \text{ A}, V_{GS} = 0$			1.5	V
t <sub>rr</sub> Q <sub>rr</sub> I <sub>RRM</sub>	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$I_{SD} = 5 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s},$ $V_{DD} = 100 \text{ V}, \text{ T}_{\text{j}} = 25^{\circ}\text{C}$ (see test circuit, see Figure 15)		93 237 5.1		ns nC A
t <sub>rr</sub> Q <sub>rr</sub> I <sub>RRM</sub>	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$\begin{split} I_{SD} &= 5 \text{ A, di/dt} = 100 \text{ A/}\mu\text{s,} \\ V_{DD} &= 100 \text{ V, } \text{T}_{\text{j}} = 150 ^{\circ}\text{C} \\ (\text{see test circuit, see Figure 15}) \end{split}$		97 286 5.9		ns nC A

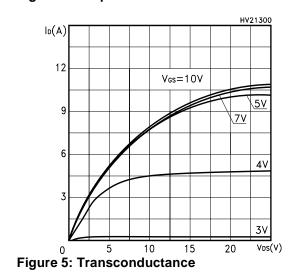
(1) Pulsed: Pulse duration = 300  $\mu$ s, duty cycle 1.5 %. (2) Starting T<sub>j</sub> =25 °C, I<sub>d</sub> = 5 A, V<sub>DD</sub> = 50 V (\*) Pulse width limited by safe operating area

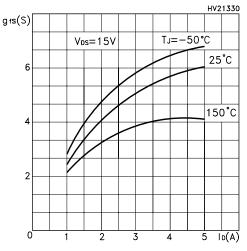
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HV21290  $I_{D}(A)$ 10 10µs 100µs 10<sup>0</sup> 1ms 10ms Π 10 Tj=150°C Tc=25°C Single pulse  $10^{-2}$ 10<sup>3</sup> V<sub>DS</sub>(V) 68 10<sup>0</sup> 68 10<sup>2</sup> 10-1 10

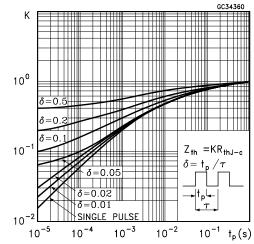
### **Figure 4: Output Characteristics**

Figure 3: Safe Operating Area





### **Figure 6: Thermal Impedance**



**Figure 7: Transfer Characteristics** 

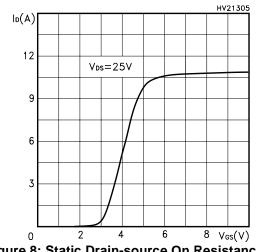
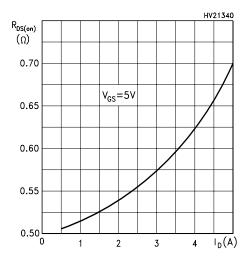


Figure 8: Static Drain-source On Resistance



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### Figure 9: Gate Charge vs Gate-source Voltage

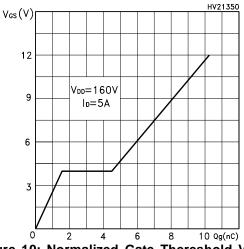


Figure 10: Normalized Gate Thereshold Voltage vs Temperature

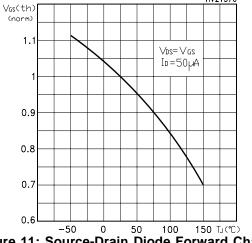
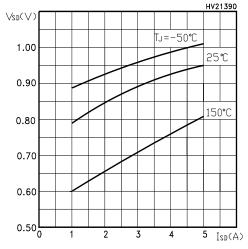


Figure 11: Source-Drain Diode Forward Characteristics



### Figure 12: Capacitance Variations

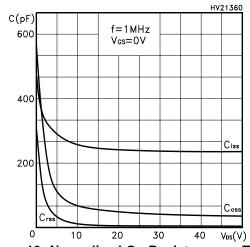
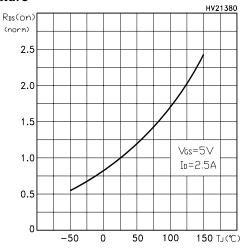


Figure 13: Normalized On Resistance vs Temperature



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# Figure 14: Switching Times Test Circuit For Resistive Load

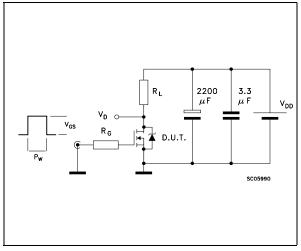
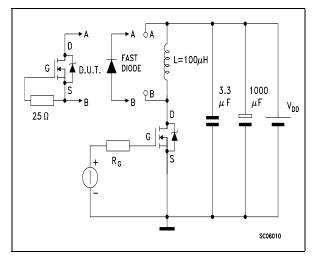
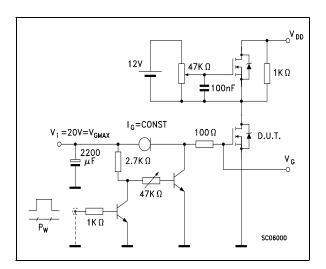


Figure 15: Test Circuit For Inductive Load Switching and Diode Recovery Times

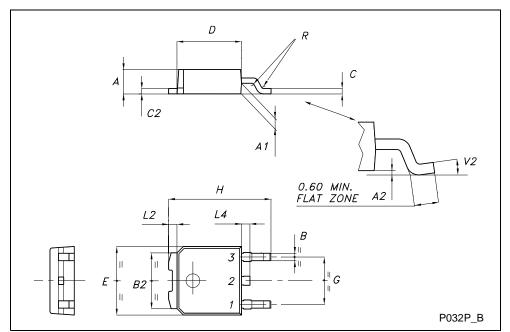


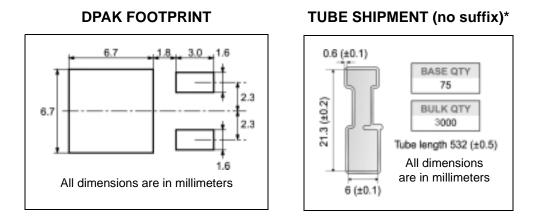
### Figure 16: Gate Charge Test Circuit



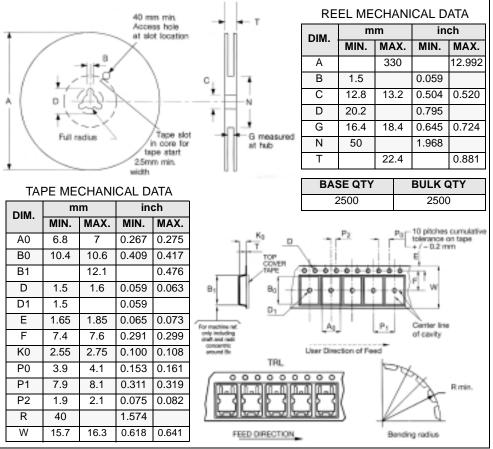
DIM.		mm			inch			
2	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.		
А	2.20		2.40	0.087		0.094		
A1	0.90		1.10	0.035		0.043		
A2	0.03		0.23	0.001		0.009		
В	0.64		0.90	0.025		0.035		
B2	5.20		5.40	0.204		0.213		
С	0.45		0.60	0.018		0.024		
C2	0.48		0.60	0.019		0.024		
D	6.00		6.20	0.236		0.244		
E	6.40		6.60	0.252		0.260		
G	4.40		4.60	0.173		0.181		
Н	9.35		10.10	0.368		0.398		
L2		0.8			0.031			
L4	0.60		1.00	0.024		0.039		

### TO-252 (DPAK) MECHANICAL DATA





### TAPE AND REEL SHIPMENT (suffix "T4")\*



\* on sales type

### Table 8: Revision History

Date	Revision	Description of Changes
08-June-2004	2	New Stylesheet. Datasheet according to PCN DSG-TRA/04/532
20-Sep-2004	3	Changes on Table 3, and on Figure 3.

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